

## ERRATUM

### Electron Probe Microanalysis of Ni Silicides Using Ni-L X-Ray Lines - ERRATUM

Xavier Llovet, Philippe T. Pinard, Erkki Heikinheimo, Seppo Louhenkilpi, and Silvia Richter

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A typographical error was published in an equation on p. 8 of “Electron Probe Microanalysis of Ni Silicides Using Ni-L X-Ray Lines” by Llovet et al. (2016), whereby a “1” was mistakenly input as a “0”. The corrected sentence and equation is published below:

Notice that  $\omega_{L_2} + a_{L_2} + f_{23} = 1$ , where  $a_{L_2}$  is the Auger yield for the  $L_2$  subshell.

We apologize for this error.

#### REFERENCE

LLOVET, X., PINARD, P.T., HEIKINHEIMO, E., LOUHENKILPI, S. & RICHTER, S. (2016). Electron probe microanalysis of Ni silicides using Ni-L X-ray lines. *Microsc Microanal* **22**, doi:<http://dx.doi.org/10.1017/S1431927616011831>.